

RELIABILITY DATA

LT1239

8/21/2006

• OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽¹⁾ AT +125°C	NUMBER OF ⁽²⁾ FAILURES
SOIC/SOT/MSOP	131 131	9426	9439	340.78 340.78	0 0

• PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SOIC/SOT/MSOP	950 950	9509	0116	27.60 27.60	0 0

• TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	550 550	9512	0116	55.00 55.00	0 0

• THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	300 300	9509	0116	30.00 30.00	0 0

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 5.40 FITS

(3) Mean Time Between Failures in Years = 21,125

Note: 1 FIT = 1 Failure in One Billion Hours.